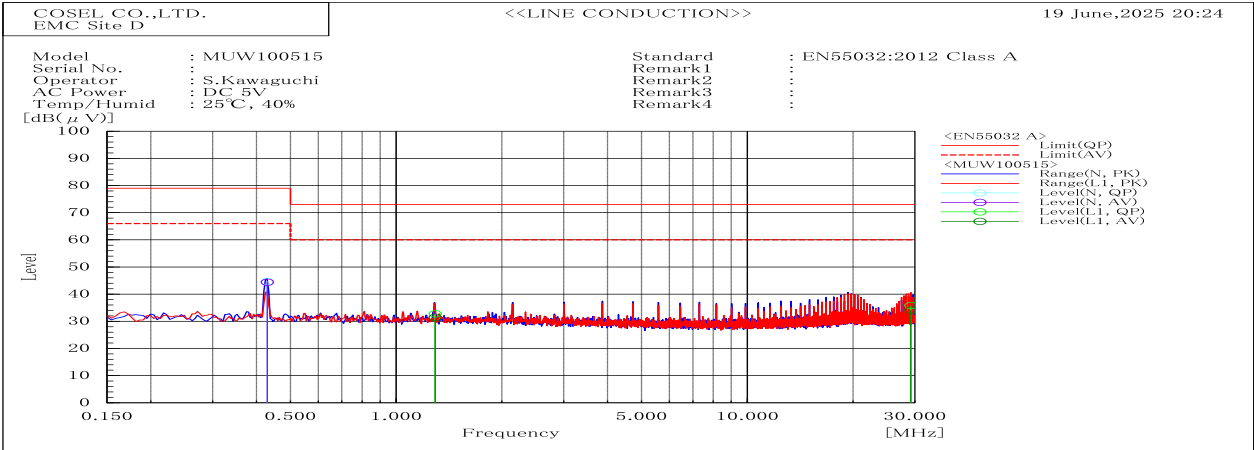
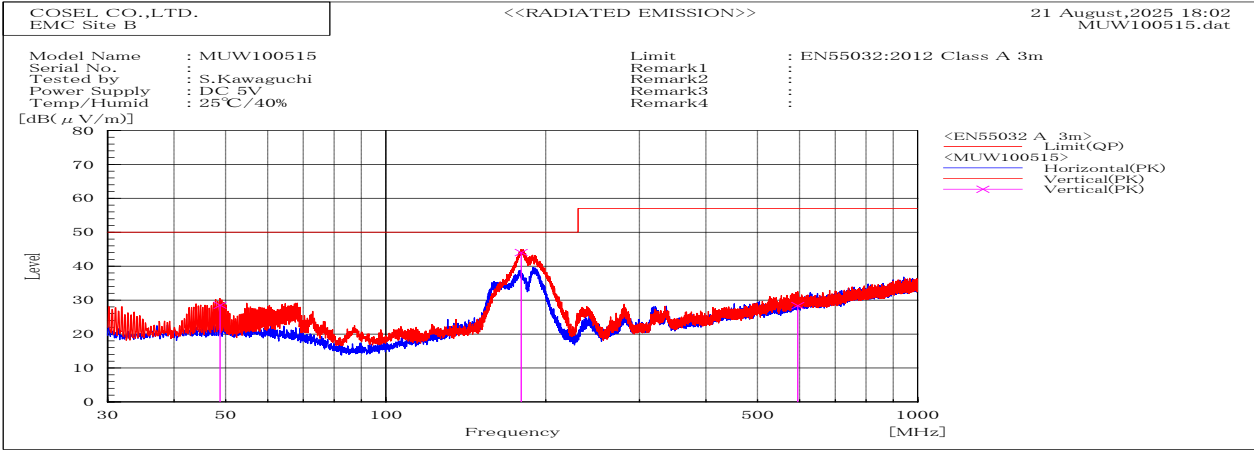


DATA SHEET		Date	21-Aug-25
Model	MUW100515	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



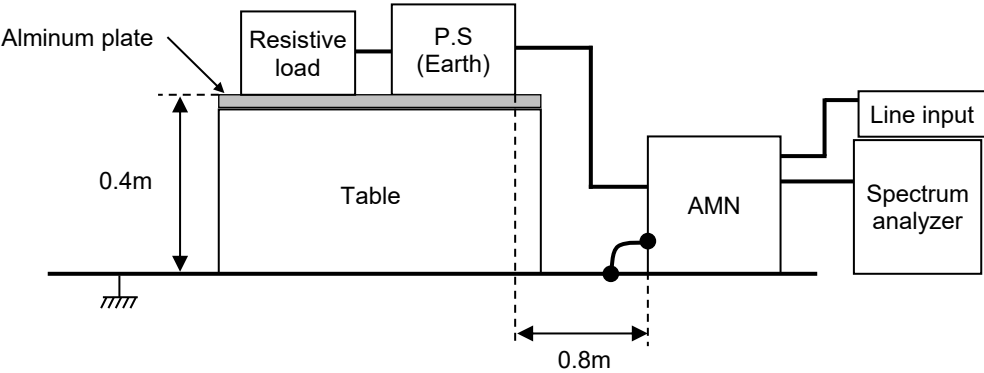
Frequency	Line	Level		Limit		Margin		Pass/Fail	Remark
MHz		dB(μV)		dB(μV)		dB			
		QP	AV	QP	AV	QP	AV		
0.429	N	44.6	44.4	79	66	34.4	21.6	Pass	
1.291	L1	32.8	31.4	73	60	40.2	28.6	Pass	
29.24	L1	35.8	34.2	73	60	37.2	25.8	Pass	



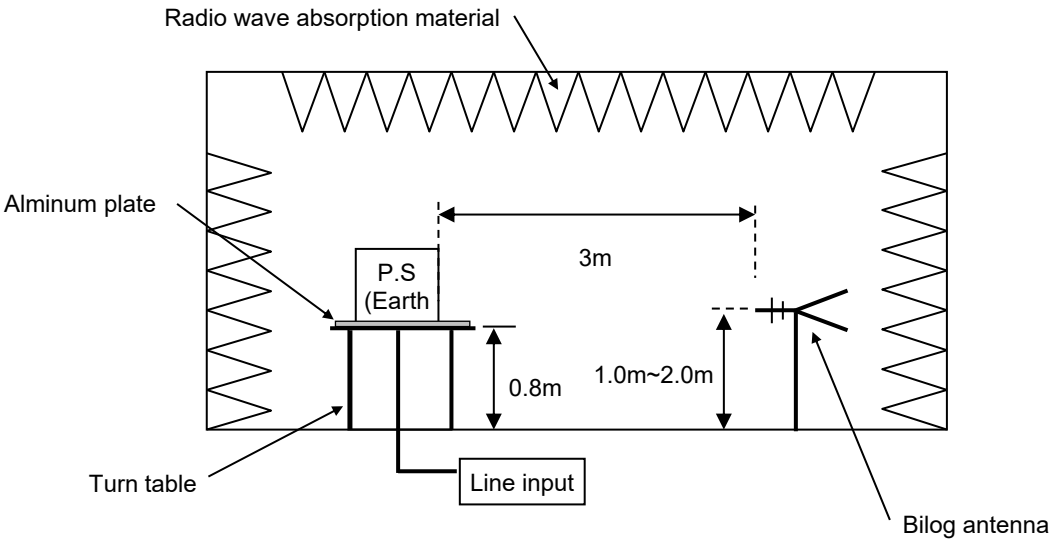
Frequency MHz	Polarization	Stability	Level	Limit	Margin	Pass/Fail	Height cm	Angle deg	Remark
			dB(uV/m) QP	dB(uV/m) QP	dB QP				
179.685	V	Stable	44	50	6	Pass	100.2	57.9	
48.799	V	Stable	28.5	50	21.5	Pass	100.2	244.7	
594.971	V	Stable	28.4	57	28.6	Pass	100.5	197.4	

DATA SHEET		Date	21-Aug-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

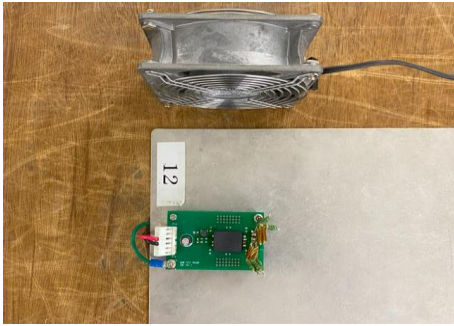
Test : EMI
Model Name: MUW10□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

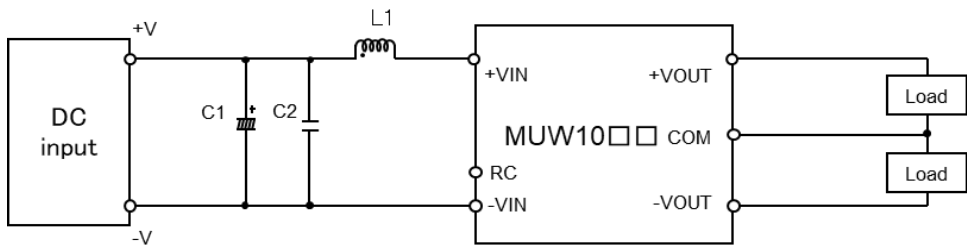


Fig.1 MUW10□□ Testing circuitry

- | | | | |
|------|----------|--------------------|---|
| C1 : | MUW1005□ | 25V 1500 μ F | Electric capacitor (LXZseries NIPPON CHEMI-CON) |
| | MUW1012□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW1024□ | — | — |
| | MUW1048□ | — | — |
| C2 : | MUW1005□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUW1012□ | 25V 10 μ F | Ceramic capacitor (CM316X7R106K25AT KYOCERA) |
| | MUW1024□ | 50V 4.7 μ F | Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING) |
| | MUW1048□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUW1005□ | 5000mA 2.2 μ H | Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING) |
| | MUW1012□ | 3500mA 4.7 μ H | Inductor(LQH5BPN4R7N38 MURATA MANUFACTURING) |
| | MUW1024□ | 1600mA 22 μ H | Inductor(LQH5BPN220M38 MURATA MANUFACTURING) |
| | MUW1048□ | 1100mA 47 μ H | Inductor(LQH5BPN470M38 MURATA MANUFACTURING) |